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| Notice of References Cited | Application/Control No. 10/721,408 | Applicant(s)/Patent Under Reexamination KAWANISHI ET AL. | |
| | Examiner Ernest F. Karlson | Art Unit 2829 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-5,272,434 | 12-1993 | Meyrueix et al. | 324/751 |
| * | B | US-5,412,330 | 05-1995 | Ravel et al. | 324/753 |
| * | C | US-5,991,036 | 11-1999 | Frankel, Michael Y. | 356/364 |
| * | D | US-6,011,402 | 01-2000 | Kuo et al. | 324/753 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | Lo et al; "Proposal for three-dimensional internal field mapping by cw electro-optic probing"; Applied Physics Letters; vol. 50; No. 25; June 22, 1987; Pages 1791-1793. |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.